PTO/SB/08a (08-03)

Approved for use through 07/31/2008. OMB 0651-0031

U.S. Patent and Trademark Office; U.S. DEPARTMENT OF COMMERCE
to a collection of Information unless it displays a valid OMR control surples.

Under the	he Paperwork Reduction A	ct of 1985, no pen	sous sue rednited to	respond to a collection of information	on unless it displays a valid OMB control number	ſ		
	shute for form 1449A/PT(Complete if Known				
				Application Number	10/723,331			
M	y NFORMATION	I DISCLO	SURE	Filing Date	November 26, 2003			
S	TATEMENT E	3Y APPLI	CANT	First Named Inventor	Liaw			
				Art Unit	TBD			
	(Use as many she	ests as necessary	v)	Examiner Name	TBD			
Sheet	1	of	1	Attorney Docket Number	TSM03-1154			
Sheet	1	of	1	Attorney Docket Number	TSM03-1154	_		

	U.S. PATENT DOCUMENTS							
Examiner Initials)	Cite No.1	Document Number	Publication Date MM-DO-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear			
		Number - Kind Code ^{2 (Fincum)}						
42	A	US-6,643,167 B2	11-04-2003	Nii				
		US-						
		US-						
		us-						
		US-						
		US-						
		US-						
		US-			T T			

FOREIGN PATENT DOCUMENTS						
Examiner Initials*	Cite No.1	Foreign Patent Document	Publication Date	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	
		Country Code ³ - Number ⁴ - Kind Code ⁵ (if known)	MM-0D-YYYY			7
					• "	
					·	1

NON PATENT LITERATURE DOCUMENTS					
Examiner Initials*	Cite No.	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T²		
M	В	DEGALAHAL, V., et al., "Analyzing Soft Errors in Leakage Optimized SRAM Design," Proc. Of 18 th International Conference on VLSI Design (January 2003) pp. 227-233.			
M	С	OSADA, K., et el., "Cosmic-Ray Multi-Error Immunity for SRAM, Based on Analysis of the Parasitic Bipolar Effect," 2003 Symposium on VLSI Circuits Digest of Technical Papers (June 2003) pp. 1-4.			
		·			

Examiner
Signature

"EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered, include copy of this form with next communication to applicant. "Applicant's unique citation designation number (optional). "See Kinds Codes of USPTO Patent Documents at www.uspto.gogy or MPEP 801.04. "Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). "For Japanese patent documents, the indication of the region of the Emperor must precede the serial number of the patent document. "Xind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. "Applicant is to place a check mark here if English language Translation is attached.

This collection of information is required by 37 CER 1 97 and 1 98. The information is required by 37 CER 1 97 and 1 98. The information is missing the constitution of the patent document.

Translation is attached.
This collection of information is required by 37 CFR 1.97 and 1.98. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application. Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.14. This collection is estimated to take 2 hours to complete, including gathering, preparing, and submitting the completed application form to the USPTO. Time will vary depending upon the individual case. Any comments on the amount of time you require to complete this form and/or suggestions for reducing this burden, should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, U.S. Department of Commerce, P.O. Box 1450, Alexandria, VA 22313-1450. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.